

INSPECTION REQUIREMENTS

RELAYS

263 AND 264 TYPE(S)

GENERAL EQUIPMENT REQUIREMENTS

COMMON SYSTEMS

TABLE 800-668-187

Lot Range	A	B	C	D	E	F	G	H	I	J	K	
Lot Size (number of relays in lot)	1	161	501	851	1251	1751	2251	3001	4001	6001	8001	
Samples Size (relays - see note 3)	All	160	180	230	280	360	400	460	500	550	600	
Inspection Item (see note 1) (For requirements, refer to Section 040-247-701 and sections of Division 800.)	Allowable Defect Numbers											
	Basis	AN	AN	AN	AN	AN	AN	AN	AN	AN	AN	AN
1. Functional, Numerical, and Group Designations (on covers and on relays)	Relay	Record all defects found. See note 2.										
2. Mounting of Relay and Relay Magnet	"	0	4	5	8	9	12	14	17	18	21	23
3. Retaining Spring Tension	"	0	1	1	2	2	4	4	5	6	7	7
4. Freedom of Movement of Armature	"	0	1	1	2	2	4	4	5	6	7	7
5. Overlap of Armature	"	0	1	1	2	2	4	4	5	6	7	7
6. Armature Travel	"	0	1	1	2	2	4	4	5	6	7	7
7. Tightness of Locknut	"	0	1	1	2	2	4	4	5	6	7	7
8. Contact Alignment	Level	0	6	7	9	12	16	18	21	23	25	28
9. Operating Spring Tension	"	0	6	7	9	12	16	18	21	23	25	28
10. Spring Clearance	"	0	6	7	9	12	16	18	21	23	25	28
11. Contact Separation	"	0	6	7	9	12	16	18	21	23	25	28
12. Front Contact Make	SI	0	6	7	9	12	16	18	21	23	25	28
13. Electrical Requirements	Relay	0	1	1	2	2	4	4	5	6	7	7

AN = Allowable Number of defects in sample

SPOTTINESS TABLE

Size of Subsample	3	26	71	126	176	201	251	301	351	401	451	501	551	601	651	701	751	801	851	901	951
	25	70	125	175	200	250	300	350	400	450	500	550	600	650	700	750	800	850	900	950	1000
SN	2	3	4	6	7	8	10	11	12	13	14	16	17	19	20	22	23	24	25	26	28

SN = Spottiness Number (applying to subsample)

Note 1: Except for relays mounted and wired during installation, inspection for this type of relay is limited to the item designated by SI (Selected

Item). Extension of inspection to the remaining items for lots in lot range A shall be made where one or more defects are found for the selected

item. Extension of inspection to the remaining items in ranges B through K shall be made when the AN is exceeded for the selected item.

Note 2: For each type of defected recorded, sufficient additional inspection shall be made to insure elimination of the irregularity in the equipment involved.

Note 3: The selection and distribution of the sample will be on the basis of the relay. When required to inspect this relay for all items (1 through 13) for lot ranges B through K, only one magnet and associated armature together with spring assemblies on three levels will be selected from each relay in the sample. The selection of magnets from the individual relays shall be such that an approximately equal number of top and bottom magnets with their associated parts will be

included. The levels selected should also be varied throughout the relays of the sample. In lot range A, the inspection for items 8 through 12 may be limited to three spring assemblies per relay. For these lots, if the total number of defects found for any of the above inspection items is in excess of $1/2$ the spottiness number (dropping fractional parts but in no case in excess of the AN of lot range B) corresponding to the number of spring assemblies inspected, the uninspected portion of the lot shall be inspected completely for that inspection item.

For detailed explanation and use of tables, refer to Section 800-668-180.

REASON FOR REISSUE

To expand note 1.